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(12) **United States Design Patent** (10) **Patent No.:** **US D804,435 S**
Taniguchi et al. (45) **Date of Patent:** **** Dec. 5, 2017**

(54) **FLAP IN AN ADHESIVE TAPE FOR SEMICONDUCTOR MANUFACTURING**

CPC H01L 21/563; H01L 21/6836; H01L 23/3157; H01L 24/81; C09J 163/00
See application file for complete search history.

(71) Applicant: **HITACHI CHEMICAL COMPANY, LTD.**, Tokyo (JP)

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(72) Inventors: **Kouhei Taniguchi**, Ichihara (JP); **Takayuki Matsuzaki**, Ichihara (JP); **Shinya Katou**, Ichihara (JP); **Kouji Komorida**, Ichihara (JP); **Michio Mashino**, Ichihara (JP); **Tatsuya Sakuta**, Ichihara (JP); **Rie Katou**, Ichihara (JP)

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(73) Assignee: **Hitachi Chemical Company, Ltd.**, Tokyo (JP)

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(**) Term: **14 Years**

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(21) Appl. No.: **29/491,391**

Office Action dated Jan. 18, 2013, in Design U.S. Appl. No. 29/413,539.

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Primary Examiner — Austin Murphy
(74) *Attorney, Agent, or Firm* — Fitch, Even, Tabin & Flannery, LLP

Related U.S. Application Data

(60) Continuation of application No. 29/413,518, filed on Feb. 16, 2012, now abandoned, which is a division of application No. 29/389,787, filed on Apr. 15, 2011, now Pat. No. Des. 656,910.

(57) **CLAIM**

The ornamental design for a flap in an adhesive tape for semiconductor manufacturing, as shown and described.

(30) **Foreign Application Priority Data**

Oct. 15, 2010 (JP) D2010-024764

DESCRIPTION

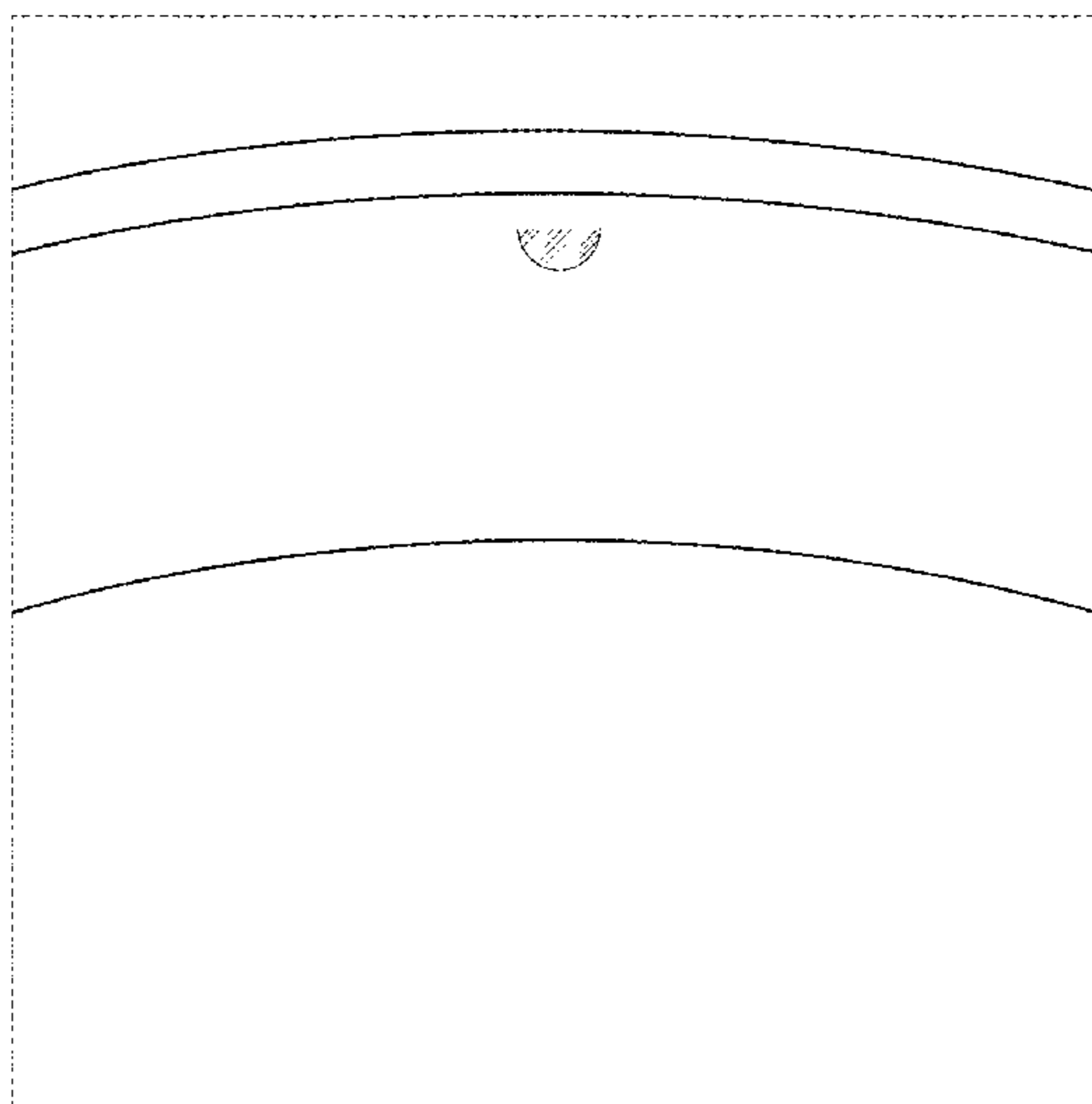
(51) **LOC (10) Cl.** **13-03**

(52) **U.S. Cl.**
USPC **D13/180**

(58) **Field of Classification Search**
USPC D10/71, 75; D19/69; D24/189;
D13/182; 33/494, 758, 562, 759;
101/288; 206/390; 40/638, 641; 428/43,
428/343, 345, 353, 114, 455; D7/585;
D20/22, 42

FIG. 1 is a top plan view of a flap in an adhesive tape for semiconductor manufacturing incorporating our new design; FIG. 2 is a bottom plan view of the flap of FIG. 1; FIG. 3 is a cross-sectional view taken at line 3-3 in FIG. 1; FIG. 4 is an enlarged view of portion 4-4, 4-4 in FIG. 1; and, FIG. 5 is a perspective view of the flap in use. The broken lines are included for the purpose of illustrating environmental structure and form no part of the claimed design.

1 Claim, 5 Drawing Sheets



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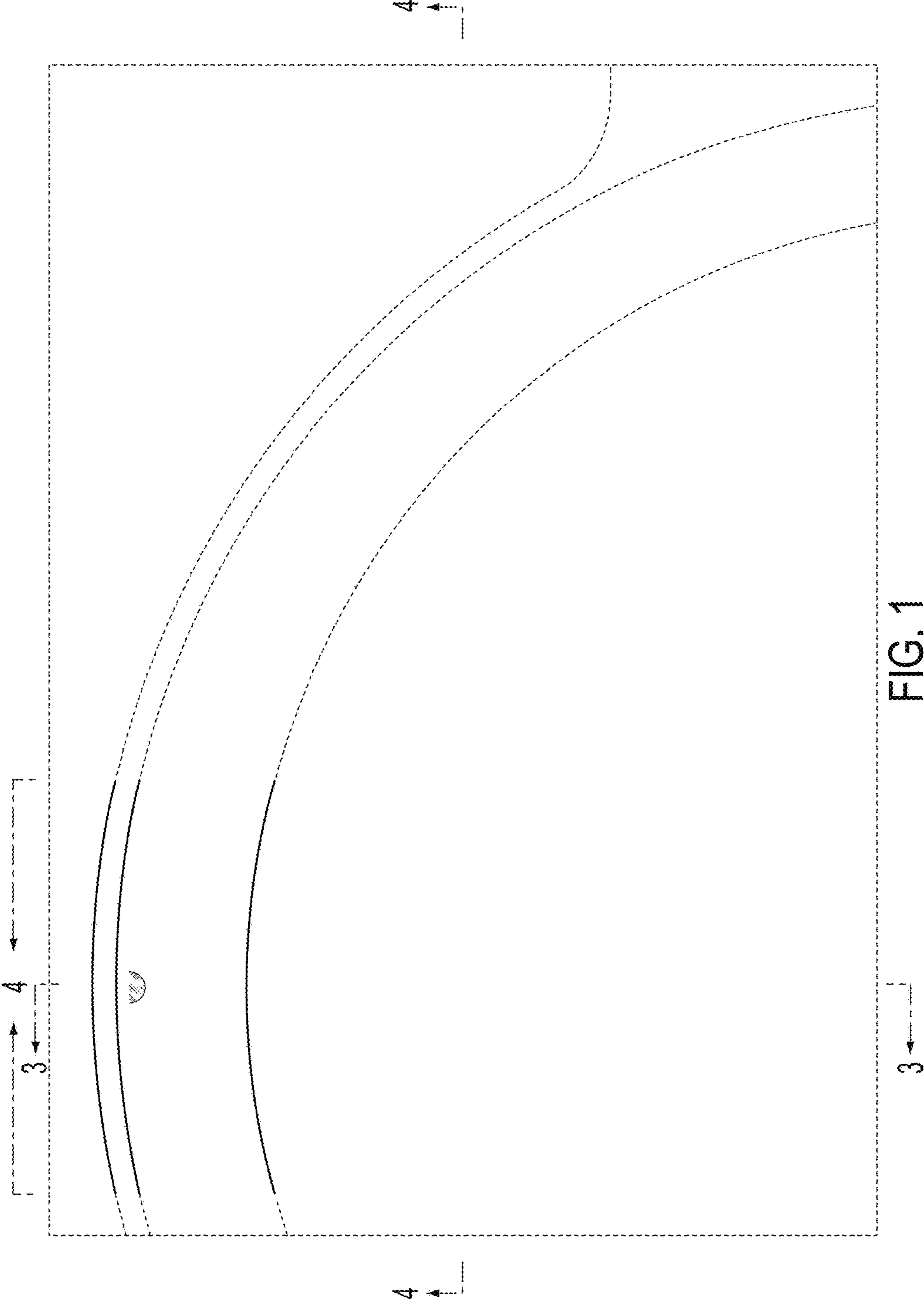


FIG. 1

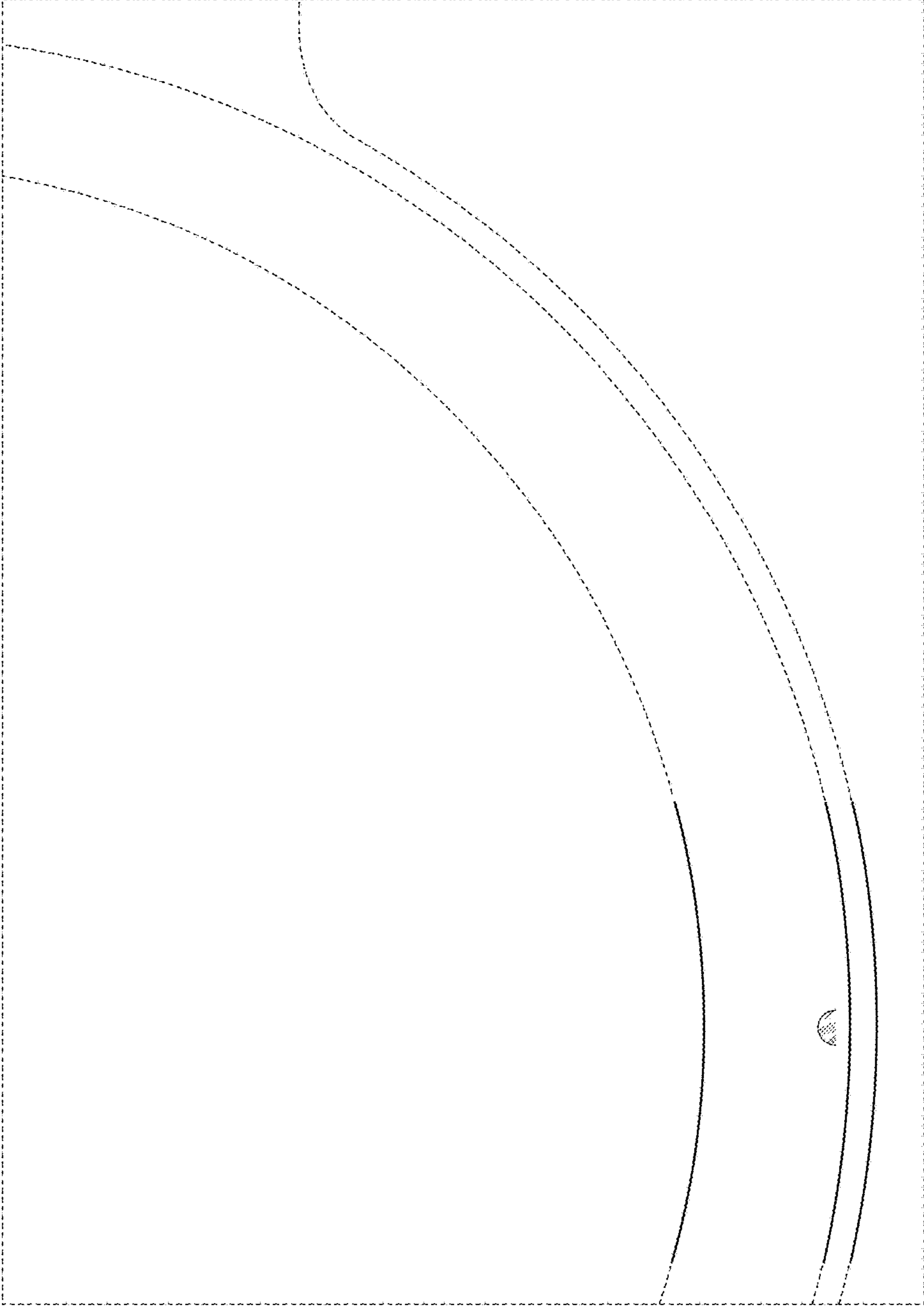


FIG. 2

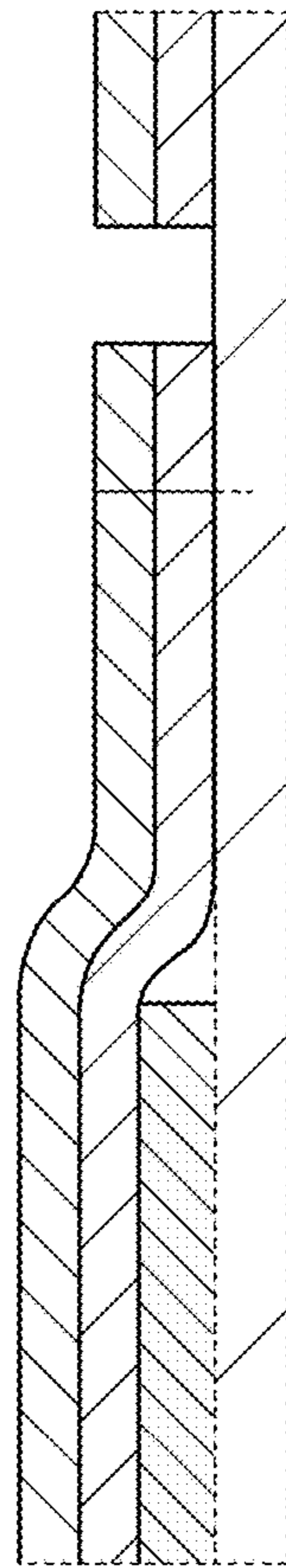


FIG. 3

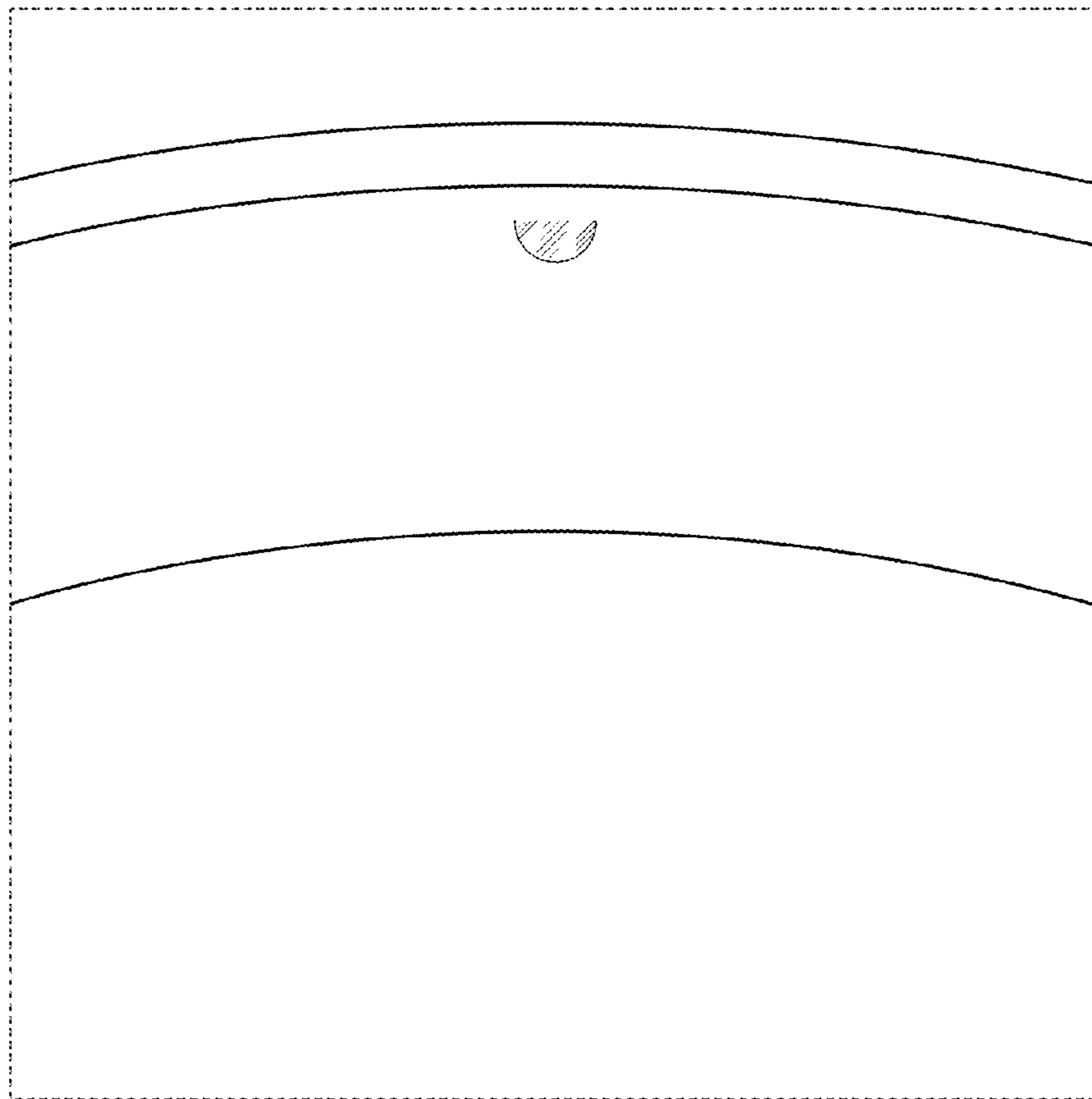


FIG. 4

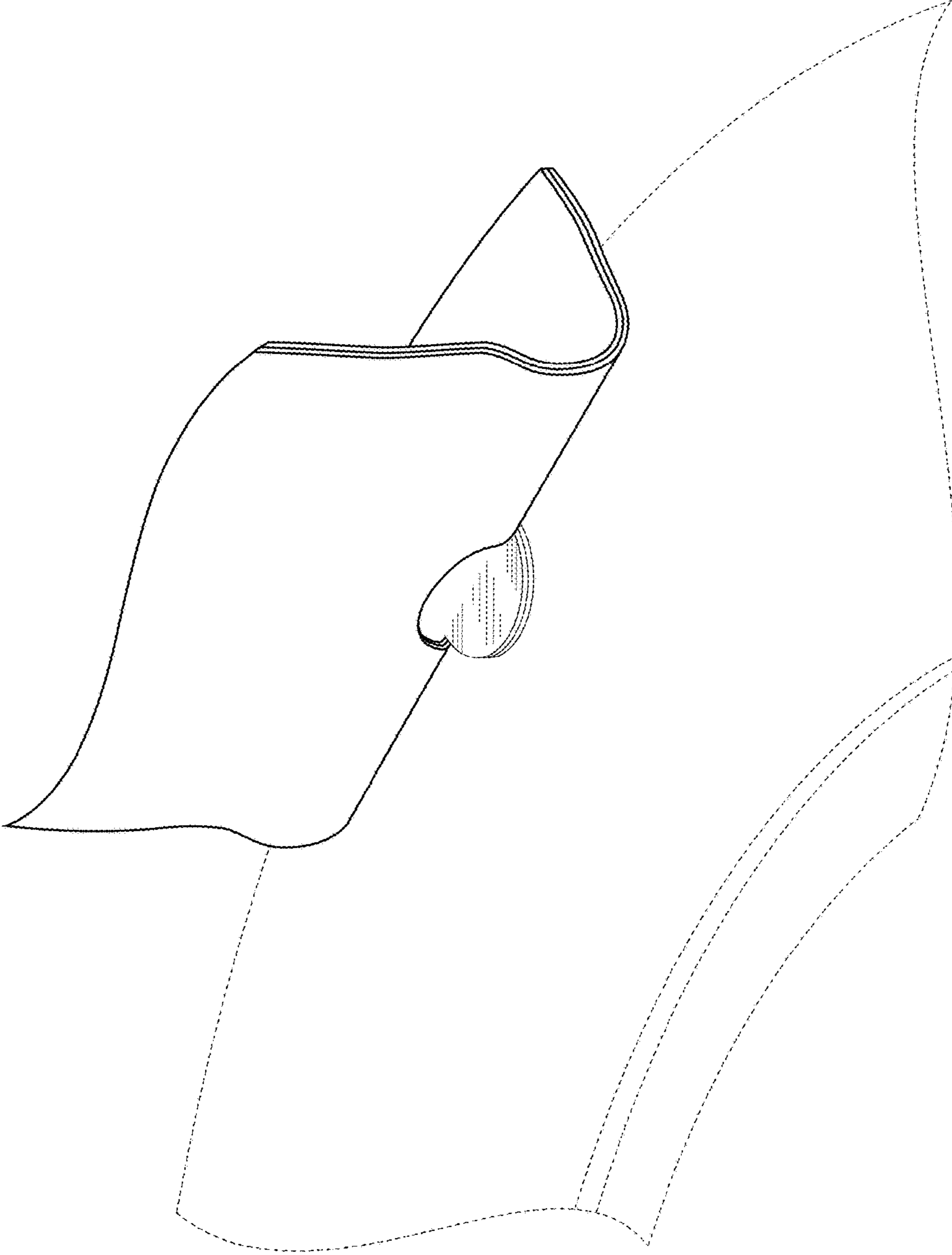


FIG. 5